30V N-Channel PowerTrench[®] MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low RDS(ON) and fast switching speed.

Applications

- DC/DC converter
- Motor drives

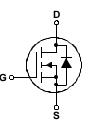
G S TO-252



- 21 A, 30 V $R_{DS(ON)} = 35 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 50 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- Low gate charge (5nC typical)
- Fast switching

.

+ High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$



Absolute Maximum Ratings TA=25°C unless otherwise noted

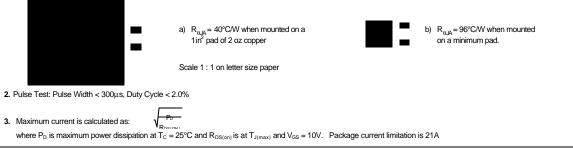
Symbol		Parameter		Ratings	Units	
V _{DSS}	Drain-Source	ce Voltage		30	V	
V _{GSS}	Gate-Source Voltage			±20	V	
b	Drain Curre	nt – Continuous	(Note 3)	21	A	
		– Pulsed	(Note 1a)	100		
PD	Power Diss	ipation	(Note 1)	28	W	
			(Note 1a)	3.2		
			(Note 1b)	1.3		
T_J, T_{STG}	Operating a	nd Storage Junction T	emperature Range	-55 to +175	°C	
Therma	I Charact	teristics				
R _{0JC}	Thermal Re	sistance, Junction-to-	Case (Note 1)	4.5	°C/W	
R _{0JA}	Thermal Re	sistance, Junction-to-A	Ambient (Note 1a)	40	°C/W	
$R_{\theta JA}$	Thermal Re	sistance, Junction-to-A	Ambient (Note 1b)	96	°C/W	
Packag	e Markin	g and Ordering	g Information			
Device		Device	Reel Size	Tape width	Quantity	

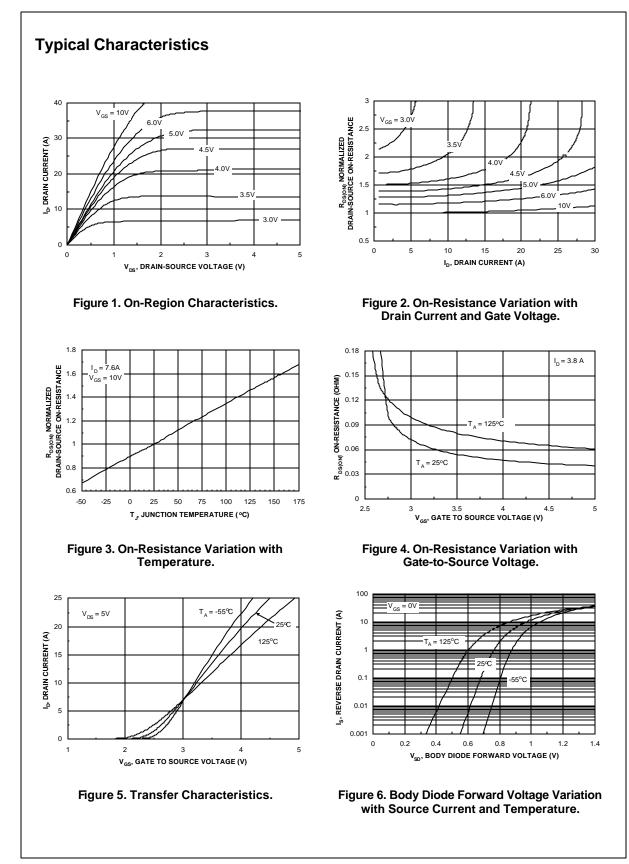
Device Marking	Device	Reel Size	Tape width	Quantity
FDD6630A	FDD6630A	13"	16mm	2500 units
			-	

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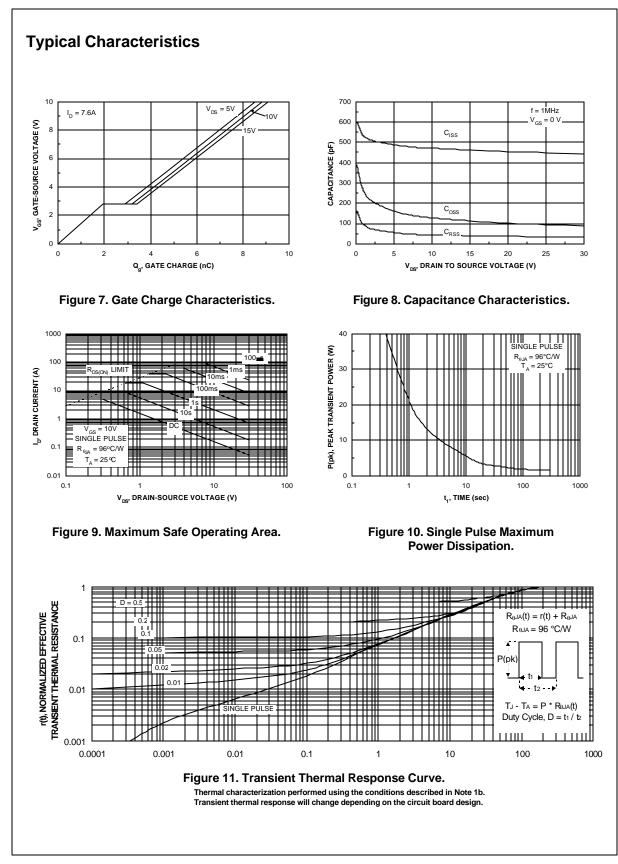
FDD6630A Rev D(W)

rce Avalanche Ratings (Note		Min	Тур	Max	Units
	2)				
Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 V$			55	mJ
Drain-Source Avalanche Current				7.6	А
cteristics					
Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	30			V
Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		23		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Gate–Body Leakage, Forward				100	nA
Gate–Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
cteristics (Note 2)					
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1	1.7	3	V
Gate Threshold Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		-4		mV/ºC
Static Drain–Source Dn–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}$		40	50	mΩ
De Otata Dirain Ourrant	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 7.6 \text{ A}, \text{ T}_{J} = 125^{\circ}\text{C}$	20	44	58	•
		20	10		A S
	$v_{DS} = 5 v$, $i_D = 7.6 A$		13		3
				1	
			-		pF
			_		pF
•			40		pF
	1/1 - 15/1 - 10		-	44	
· · · · · · · · · · · · · · · · · · ·			-		ns
	$V_{\rm GS} = 10^{-1}$, $N_{\rm GEN} = 0.22$		-		ns
,				-	ns ns
	$V_{DS} = 15 V$ $h = 7.6 A$		-		nC
	$V_{GS} = 5 V$		-	1	nC
•					nC
Ū.	and Maximum Patinga		1.4		no
				27	A
Drain–Source Diode Forward /oltage	$V_{GS} = 0 \text{ V}, $		0.8	1.2	V
	Arain–Source Breakdown Voltage ireakdown Voltage Temperature coefficient ero Gate Voltage Drain Current Gate–Body Leakage, Forward Gate–Body Leakage, Reverse teristics (Note 2) Gate Threshold Voltage emperature Coefficient itatic Drain–Source On–State Drain Current orward Transconductance Characteristics Dut Capacitance Everse Transfer Capacitance Characteristics (Note 2) furn–On Delay Time furn–On Rise Time furn–Off Fall Time otal Gate Charge Gate–Drain Charge rce Diode Characteristics Market Diade Forward Total Gate Charge Characteristics	Invarian—Source Breakdown Voltage Treakdown Voltage Temperature Coefficient $V_{GS} = 0 V, b = 250 \mu A$ b = 250 μA , Referenced to 25°Cero Gate Voltage Drain Current Sate—Body Leakage, Forward $V_{GS} = 24 V, V_{GS} = 0 V$ $V_{GS} = 0 V$ Sate—Body Leakage, Reverse $V_{GS} = 20 V, V_{DS} = 0 V$ Sate—Body Leakage, Reverse $V_{GS} = -20 V, V_{DS} = 0 V$ Sate—Body Leakage, Reverse $V_{GS} = -20 V, V_{DS} = 0 V$ Sate—Body Leakage, Reverse $V_{GS} = 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Transconductance $V_{DS} = 5 V, b = 7.6 A$ 13characteristics $V_{DS} = 15 V, V_{GS} = 0 V, f = 1.0 MHz$ 113thur-On Rise Time $V_{DS} = 15 V, b = 7.6 A$ 13urn-On Rise Time $V_{OS} = 15 V, b = 7.6 A, j = 113$ 113urn-On Rise Time $V_{OS} = 15 V, b = 7.6 A, j = 113$ 24urn-Off Pall Time $V_{OS} = 15 V, b = 7.6 A, j = 113$ 24urn-Off Belay Time $V_{OS} = 15 V, b = 7.6 A, j = 13$ 24urn-Off Fall Time 2 2324otal Gate Charge $V_{OS} = 5 V$ 22iate-Drain Charge $V_{OS} = 5 V, b = 7.6 A, j = 2$ 2iate-Drain Charge 1.4 1.4recode Characteristics and Maximum R





FDD6630A Rev. D(W)



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